

ABSTRACT

A device analysis apparatus 1 is a device analysis apparatus for determining a quality of a power semiconductor device P, including an application unit 12 that applies a voltage signal to the power semiconductor device P, a light detection unit 13 that detects light from the power semiconductor device P at a plurality of detection positions A to D and outputs detection signals based on detection results, and a determination unit 33 that determines the quality of the power semiconductor device P based on temporal changes of the detection signals.

Figure 1